

SPECIFICATION AMENDMENTS

Please amend the Specification as shown below.

[0131] If the operating word line programming voltage is not the same value as the operating word line read voltage, then the word line RC time constant has to be small in order to make it possible for the word line to rapidly change voltages between program and verify. The low word line RC time constant will also facilitate the rapid change of the word line voltage many times during every read or verify in order to reduce noise as described in U.S. patent application number 10/052,924, filed January 18, 2002, entitled "Noise Reduction Technique for Transistors and Small Devices Utilizing an Episodic Agitation," now patent number 6,850,441, which is incorporated by reference. Very high operating word line voltages are intended to provide a significant part of the voltage coupled to the floating gate during programming or erase operations. So a high select-gate coupling ratio is desired. A high select gate coupling ratio will allow the word line to take over from the control line the role of being the electrode that supplies the agitating stimuli that help to reduce the effects of noise. Since the thousands of cells that are being read or verified at any given time belong to one, or at most a few, word lines, providing the high voltage and high frequency agitating stimuli to just a few word lines becomes feasible from a power consumption point of view, where as to deliver the agitating stimuli through control lines would require thousands of control lines to rapidly make several transitions of multiple volts for each single verify operation. The associated power consumption of delivering the agitating stimuli through the control line would be prohibitive.